











#### LM2902LV, LM2904LV

ZHCSIS0B - SEPTEMBER 2018-REVISED OCTOBER 2019

# LM290xLV 行业标准、低电压运算放大器

## 1 特性

- 适用于成本敏感型系统的行业标准放大器
- 低输入失调电压: ±1mV
- 共模电压范围包括接地
- 单位增益带宽: 1MHz
- 低宽带噪声: 40nV/√Hz
- 低静态电流: 90µA/通道
- 单位增益稳定
- 可在 2.7V 至 5.5V 的电源电压下运行
- 提供双通道和四通道型号
- 严格的 ESD 规格: 2kV HBM
- 工作温度范围: -40°C 至 125°C

#### 2 应用

- 无线电器
- 不间断电源
- 电池组、充电器和测试设备
- 电源模块
- 环境传感器信号调节
- 现场变送器:温度传感器
- 示波器、数字万用表和信号分析器
- 机架式服务器
- HVAC: 暖通空调
- 直流电机控制
- 低侧电流检测

## 3 说明

LM290xLV 系列包括双路 LM2904LV 和四路 LM2902LV 运算放大器。这些器件由 2.7V 至 5.5V 的 低电压供电。

这些运算放大器可以替代低电压 应用 中替代 LM321、LM358 和 LM324。某些 应用 是大型电器、烟雾探测器和个人电子产品。LM290xLV 器件在低电压下可提供比 LM290x 器件更佳的性能,并且功耗更低。这些运算放大器具有单位增益稳定性,并且在过驱情况下不会出现相位反转。ESD 设计为 LM290xLV 系列提供了至少 2kV 的 HBM 规格。

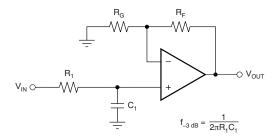
LM290xLV 系列采用行业标准封装。这些封装包括 SOIC、VSSOP 和 TSSOP 封装。

#### 器件信息<sup>(1)</sup>

88 TT TR 10:							
器件型号	封装	封装尺寸(标称值)					
LM2902LV	SOIC (14)	8.65mm × 3.91mm					
	TSSOP (14)	4.40mm × 5.00mm					
	SOIC (8)	3.91mm × 4.90mm					
LM2904LV	TSSOP (8)	3.00mm × 4.40mm					
LIVIZ9U4LV	SOT-23 (8)	1.60mm × 2.90mm					
	VSSOP (8)	3.00mm × 3.00mm					

(1) 如需了解所有可用封装,请参阅数据表末尾的可订购产品附录。

#### 单极低通滤波器



$$\frac{V_{OUT}}{V_{IN}} = \left(1 + \frac{R_F}{R_G}\right) \left(\frac{1}{1 + sR_1C_1}\right)$$

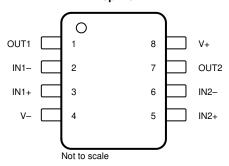


	目哀	录		
1 2 3 4 5 6	说明	8 9 10 11	10.1 Layout Guidelines	
	修订历史记录 nges from Revision A (May 2019) to Revision B			Page
•	已删除 删除了 SOT-23 (DDF) 的所有预览符号			1
Cha	nges from Original (September 2018) to Revision A			Page



## 5 Pin Configuration and Functions

### LM2904LV D, DGK, PW, DDF Packages 8-Pin SOIC, VSSOP, TSSOP, SOT-23 Top View

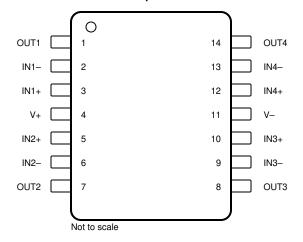


## Pin Functions: LM2904LV

PIN		1/0	DESCRIPTION			
NAME	NO.	I/O	DESCRIPTION			
IN1-	2	I	Inverting input, channel 1			
IN1+	3	I	Noninverting input, channel 1			
IN2-	6	I	Inverting input, channel 2			
IN2+	5	I	Noninverting input, channel 2			
OUT1	1	0	Output, channel 1			
OUT2	7	0	Output, channel 2			
V-	4	I or —	Negative (low) supply or ground (for single-supply operation)			
V+	8	I	Positive (high) supply			



### LM2902LV D, PW Packages 14-Pin SOIC, TSSOP Top View



## Pin Functions: LM2902LV

F	PIN	1/0	DESCRIPTION					
NAME	NO.	I/O	DESCRIPTION					
IN1-	2	ı	Inverting input, channel 1					
IN1+	3	ı	Noninverting input, channel 1					
IN2-	6	ı	Inverting input, channel 2					
IN2+	5	ı	Noninverting input, channel 2					
IN3-	9	I	Inverting input, channel 3					
IN3+	10	ı	Noninverting input, channel 3					
IN4-	13	ı	Inverting input, channel 4					
IN4+	12	ı	Noninverting input, channel 4					
OUT1	1	0	Output, channel 1					
OUT2	7	0	Output, channel 2					
OUT3	8	0	Output, channel 3					
OUT4	14	0	Output, channel 4					
V-	11	I or —	Negative (low) supply or ground (for single-supply operation)					
V+	4	I	Positive (high) supply					



## 6 Specifications

## 6.1 Absolute Maximum Ratings

over operating junction temperature range (unless otherwise noted)<sup>(1)</sup>

			MIN	MAX	UNIT	
Supply voltage, ([V+] -	- [V-])		0	6	V	
	Voltage <sup>(2)</sup>	Common-mode	(V-) - 0.5	(V+) + 0.5	V	
Signal input pins	Voltage\2	Differential	(V+) - (V-) + 0.2		V	
	Current <sup>(2)</sup>		-10	10	mA	
Output short-circuit (3)			Continuous			
Operating, T <sub>A</sub>			-55	125	°C	
Operating junction temperature, T <sub>J</sub>				150	°C	
Storage temperature, T <sub>stg</sub>			-65	150	°C	

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### 6.2 ESD Ratings

			VALUE	UNIT
V		Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>	±2000	V
V <sub>(ESD)</sub> Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 (2)	±1000	V	

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

#### 6.3 Recommended Operating Conditions

over operating junction temperature range (unless otherwise noted)

		MIN	MAX	UNIT
V <sub>S</sub>	Supply voltage [(V+) - (V-)]	2.7	5.5	V
V <sub>IN</sub> I	nput-pin voltage range	(V-) - 0.1	(V+) - 1	V
T <sub>A</sub>	Specified temperature	-40	125	°C

<sup>(2)</sup> Input pins are diode-clamped to the power-supply rails. Input signals that may swing more than 0.5 V beyond the supply rails must be current limited to 10 mA or less.

<sup>(3)</sup> Short-circuit to ground, one amplifier per package.

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



## 6.4 Thermal Information: LM2904LV

		LM2904LV					
	THERMAL METRIC <sup>(1)</sup>	D (SOIC)	DGK (VSSOP)	PW (TSSOP)	DDF (SOT-23)	UNIT	
		8 PINS	8 PINS	8 PINS	8 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	207.9	201.2	200.7	183.7	°C/W	
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	92.8	85.7	95.4	112.5	°C/W	
$R_{\theta JB}$	Junction-to-board thermal resistance	129.7	122.9	128.6	98.2	°C/W	
ΨЈТ	Junction-to-top characterization parameter	26	21.2	27.2	18.8	°C/W	
ΨЈВ	Junction-to-board characterization parameter	127.9	121.4	127.2	97.6	°C/W	

<sup>(1)</sup> For more information about traditional and new thermal metrics, see Semiconductor and IC Package Thermal Metrics.



## 6.5 Thermal Information: LM2902LV

		LM2	LM2902LV			
	THERMAL METRIC <sup>(1)</sup>	D (SOIC)	PW (TSSOP)	UNIT		
		14 PINS	14 PINS			
$R_{\theta JA}$	Junction-to-ambient thermal resistance	102.1	148.3	°C/W		
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	56.8	68.1	°C/W		
$R_{\theta JB}$	Junction-to-board thermal resistance	58.5	92.7	°C/W		
ΨЈТ	Junction-to-top characterization parameter	20.5	16.9	°C/W		
ΨЈВ	Junction-to-board characterization parameter	58.1	91.8	°C/W		

<sup>(1)</sup> For more information about traditional and new thermal metrics, see Semiconductor and IC Package Thermal Metrics.



## **6.6 Electrical Characteristics**

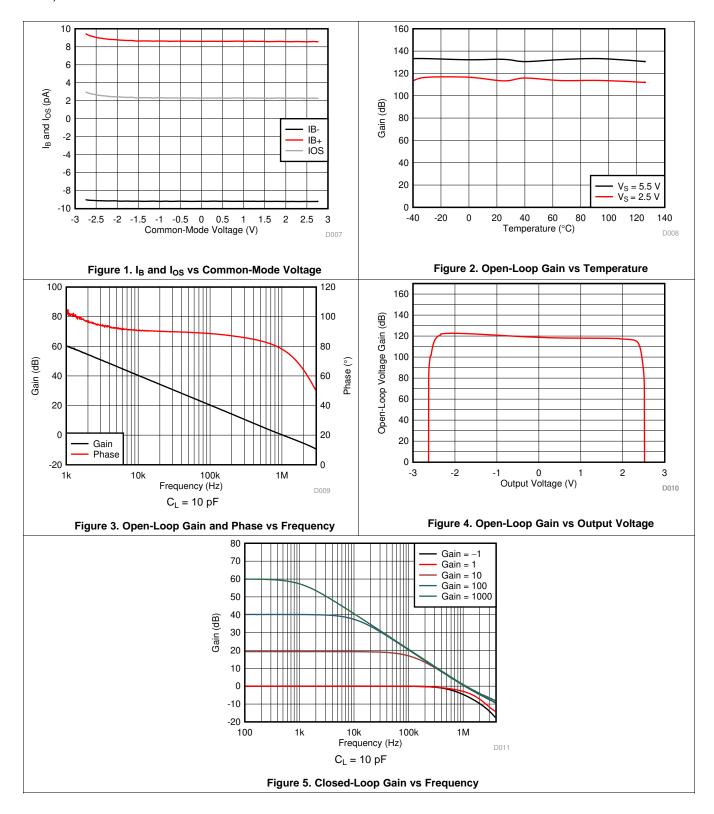
For  $V_S = (V+) - (V-) = 2.7 \text{ V}$  to 5.5 V (±1.35 V to ±2.75 V),  $T_A = 25^{\circ}\text{C}$ ,  $R_L = 10 \text{ k}\Omega$  connected to  $V_S$  / 2, and  $V_{CM} = V_{OUT} = V_S$  / 2 (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFFSET V	OLTAGE				•	
.,	leavet effect wellens	V <sub>S</sub> = 5 V		±1	±3	
Vos	Input offset voltage	$V_S = 5 \text{ V}, T_A = -40 ^{\circ}\text{C} \text{ to } 125 ^{\circ}\text{C}$				mV
dV <sub>os</sub> /dT	V <sub>OS</sub> vs temperature	$T_A = -40^{\circ}\text{C to } 125^{\circ}\text{C}$		±4		μV/°C
PSRR	Power-supply rejection ratio	V <sub>S</sub> = 2.7 V to 5.5 V, V <sub>CM</sub> = (V–)	80	100		dB
INPUT VOL	TAGE RANGE		'			
V <sub>CM</sub>	Common-mode voltage range	No phase reversal	(V-) - 0.1	(V+	-) – 1	V
OMPR	Ourse and a sale attended	$V_S = 2.7 \text{ V, (V-)} - 0.1 \text{ V} < V_{CM} < (V+) - 1 \text{ V}$ $T_A = -40^{\circ}\text{C to } 125^{\circ}\text{C}$		84		-ID
CMRR	Common-mode rejection ratio	$V_S = 5.5 \text{ V}, (V-) - 0.1 \text{ V} < V_{CM} < (V+) - 1 \text{ V}$ $T_A = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	63	92		dB
INPUT BIAS	S CURRENT					
I <sub>B</sub>	Input bias current	V <sub>S</sub> = 5 V		±15		pA
los	Input offset current			±5		pA
NOISE		-	T.			
En	Input voltage noise (peak-to-peak)	$f$ = 0.1 Hz to 10 Hz, $V_S$ = 5 V		5.1		μV <sub>PP</sub>
e <sub>n</sub>	Input voltage noise density	$f = 1 \text{ kHz}, V_S = 5 \text{ V}$		40		nV/√Hz
INPUT CAP	PACITANCE		-			
C <sub>ID</sub>	Differential			2		pF
C <sub>IC</sub>	Common-mode			5.5		pF
OPEN-LOO	P GAIN					
		$V_S = 2.7 \text{ V}, (V-) + 0.15 \text{ V} < V_O < (V+) - 0.15 \text{ V}, R_L = 2 \text{ k}\Omega$		110		dB
A <sub>OL</sub>	Open-loop voltage gain	$V_S = 5.5 \text{ V}, (V-) + 0.15 \text{ V} < V_O < (V+) - 0.15 \text{ V}, R_L = 2 \text{ k}\Omega$		125		
FREQUENC	CY RESPONSE				,	
GBW	Gain-bandwidth product	V <sub>S</sub> = 5 V		1		MHz
φ <sub>m</sub>	Phase margin	V <sub>S</sub> = 5.5 V, G = 1		75		۰
SR	Slew rate	V <sub>S</sub> = 5 V		1.5		V/µs
		To 0.1%, V <sub>S</sub> = 5 V, 2-V step, G = 1, C <sub>L</sub> = 100 pF		4		
t <sub>s</sub>	Settling time	To 0.01%, V <sub>S</sub> = 5 V, 2-V step, G = 1, C <sub>L</sub> = 100 pF		5		μs
t <sub>or</sub>	Overload recovery time	$V_S = 5 \text{ V}, V_{IN} \times \text{gain} > V_S$		1		μs
THD+N	Total harmonic distortion + noise	$\rm V_S=5.5~V, V_{CM}=2.5~V, V_O=1~V_{RMS}, ~G=1, \it f=1~kHz, ~80-kHz$ measurement BW		0.005%		
OUTPUT			'			
V <sub>OH</sub>	Voltage output swing from positive supply	$R_L \ge 2 \text{ k}\Omega$ , $T_A = -40 ^{\circ}\text{C}$ to 125 $^{\circ}\text{C}$	1			V
V <sub>OL</sub>	Voltage output swing from negative supply	$R_L \le 10 \text{ k}\Omega$ , $T_A = -40^{\circ}\text{C}$ to $125^{\circ}\text{C}$		40	75	mV
sc	Short-circuit current	V <sub>S</sub> = 5.5 V		±40		mA
Z <sub>o</sub>	Open-loop output impedance	V <sub>S</sub> = 5 V, <i>f</i> = 1 MHz		1200		Ω
POWER SU	JPPLY					
Vs	Specified voltage range		2.7 (±1.35)	5.5 (±	2.75)	V
	0	$I_0 = 0 \text{ mA}, V_S = 5.5 \text{ V}$ 90 150				
lα	Quiescent current per amplifier	I <sub>O</sub> = 0 mA, V <sub>S</sub> = 5.5 V, T <sub>A</sub> = -40°C to 125°C			160	μA



## 6.7 Typical Characteristics

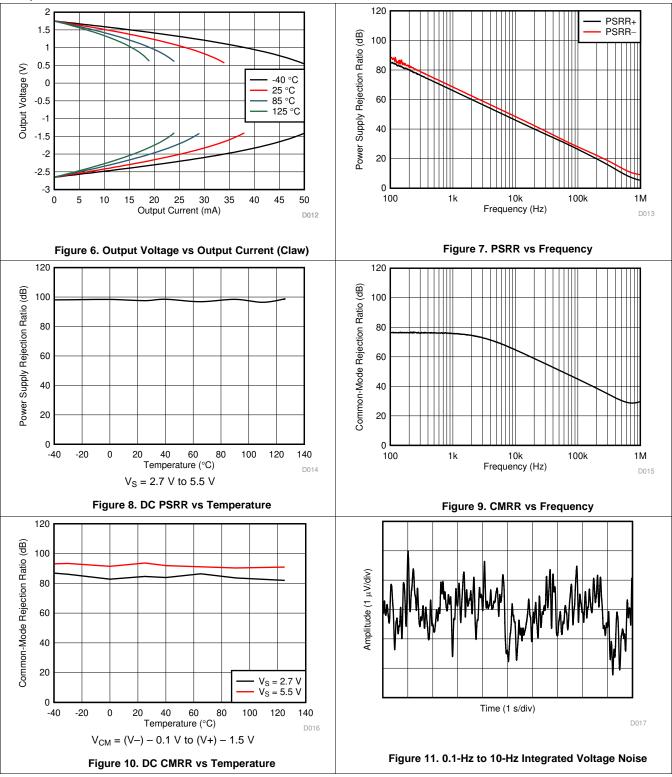
at  $T_A = 25$ °C,  $V_{+} = 2.75$  V,  $V_{-} = -2.75$  V,  $R_L = 10$  k $\Omega$  connected to  $V_S$  / 2,  $V_{CM} = V_S$  / 2, and  $V_{OUT} = V_S$  / 2 (unless otherwise noted)



# TEXAS INSTRUMENTS

## **Typical Characteristics (continued)**

at  $T_A$  = 25°C, V+ = 2.75 V, V- = -2.75 V,  $R_L$  = 10 k $\Omega$  connected to  $V_S$  / 2,  $V_{CM}$  =  $V_S$  / 2, and  $V_{OUT}$  =  $V_S$  / 2 (unless otherwise noted)





## **Typical Characteristics (continued)**

at  $T_A$  = 25°C, V+ = 2.75 V, V- = -2.75 V,  $R_L$  = 10 k $\Omega$  connected to  $V_S$  / 2,  $V_{CM}$  =  $V_S$  / 2, and  $V_{OUT}$  =  $V_S$  / 2 (unless otherwise noted)

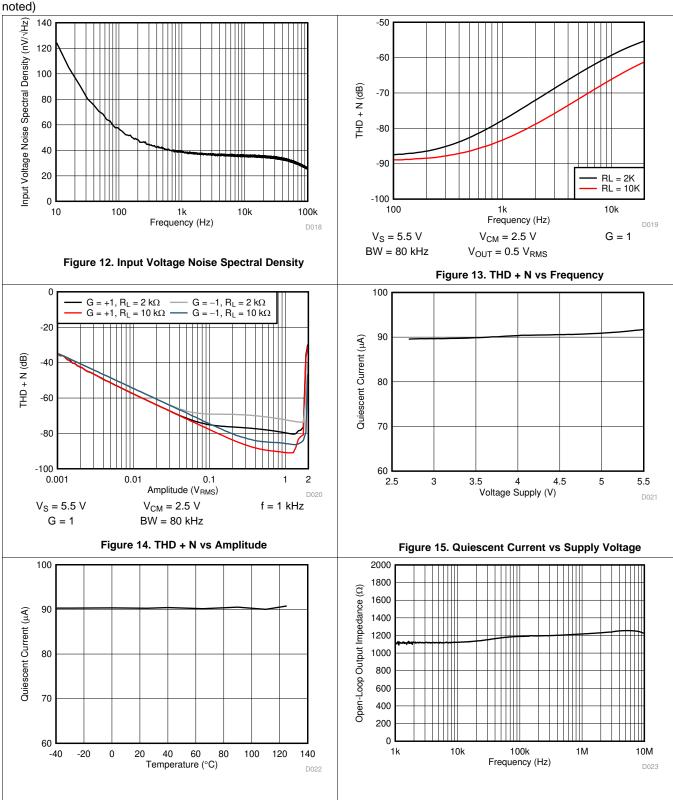


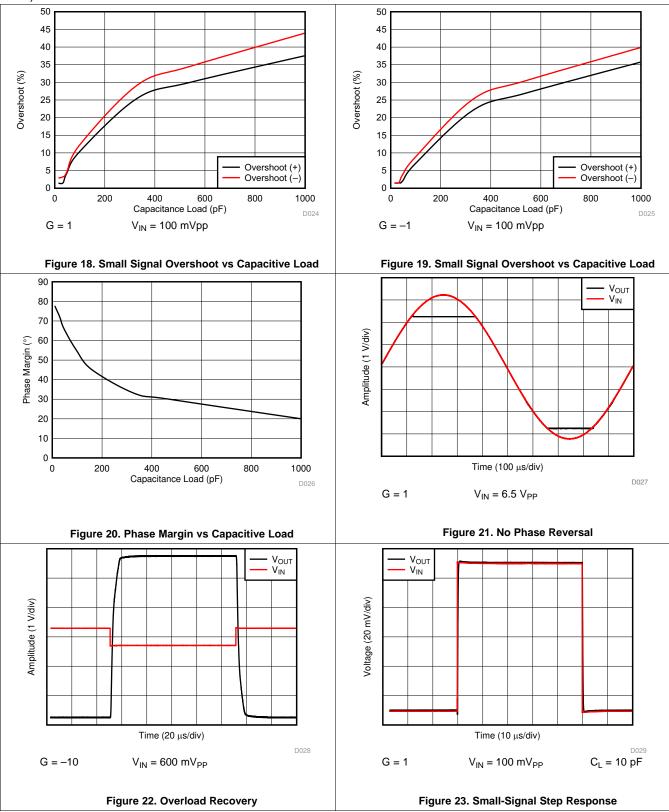
Figure 16. Quiescent Current vs Temperature

Figure 17. Open-Loop Output Impedance vs Frequency



## **Typical Characteristics (continued)**

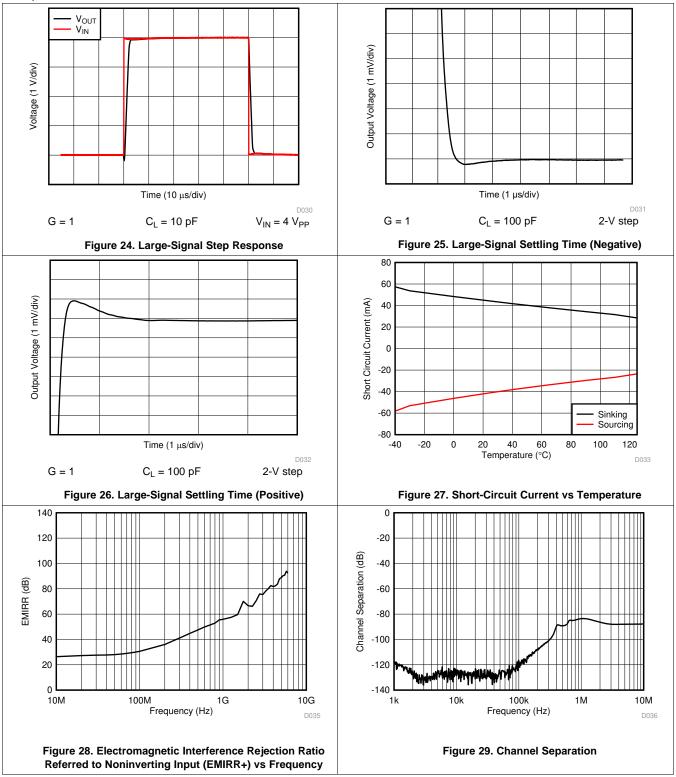
at  $T_A$  = 25°C, V+ = 2.75 V, V- = -2.75 V,  $R_L$  = 10 k $\Omega$  connected to  $V_S$  / 2,  $V_{CM}$  =  $V_S$  / 2, and  $V_{OUT}$  =  $V_S$  / 2 (unless otherwise noted)





## **Typical Characteristics (continued)**

at  $T_A$  = 25°C, V+ = 2.75 V, V- = -2.75 V,  $R_L$  = 10 k $\Omega$  connected to  $V_S$  / 2,  $V_{CM}$  =  $V_S$  / 2, and  $V_{OUT}$  =  $V_S$  / 2 (unless otherwise noted)



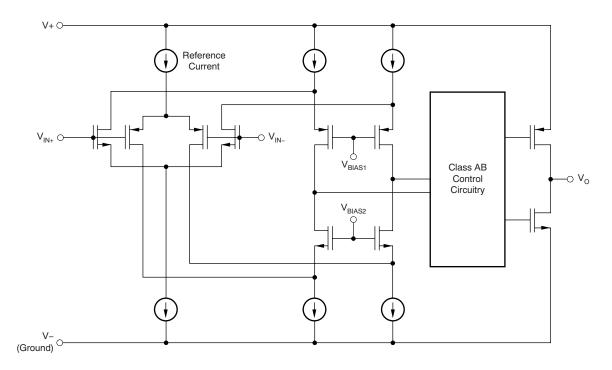


## 7 Detailed Description

#### 7.1 Overview

The LM290xLV family of low-power op amps is intended for cost-optimized systems. These devices operate from 2.7 V to 5.5 V, are unity-gain stable, and are designed for a wide range of general-purpose applications. The input common-mode voltage range includes the negative rail and allows the LM290xLV family to be used in many single-supply applications.

#### 7.2 Functional Block Diagram



#### 7.3 Feature Description

#### 7.3.1 Operating Voltage

The LM290xLV family of op amps is specified for operation from 2.7 V to 5.5 V. In addition, many specifications apply from –40°C to 125°C. Parameters that vary significantly with operating voltages or temperature are shown in the *Electrical Characteristics* section.

## 7.3.2 Common-Mode Input Range Includes Ground

The input common-mode voltage range of the LM290xLV family extends to the negative supply rail and within 1 V below the positive rail for the full supply voltage range of 2.7 V to 5.5 V. This performance is achieved with a P-channel differential pair, as shown in the *Functional Block Diagram*. Additionally, a complementary N-channel differential pair has been included in parallel to eliminate issues with phase reversal that are common with previous generations of op amps. However, the N-channel pair is not optimized for operation, and significant performance degradation occurs while this pair is operational. TI recommends limiting any voltage applied at the inputs to at least 1 V below the positive supply rail (V+) to ensure that the op amp conforms to the specifications detailed in the *Electrical Characteristics* section.



#### **Feature Description (continued)**

#### 7.3.3 Overload Recovery

Overload recovery is defined as the time required for the operational amplifier output to recover from a saturated state to a linear state. The output devices of the operational amplifier enter a saturation region when the output voltage exceeds the specified output voltage swing, because of the high input voltage or the high gain. After the device enters the saturation region, the charge carriers in the output devices require time to return to the linear state. After the charge carriers return to the linear state, the device begins to slew at the specified slew rate. Therefore, the propagation delay (in case of an overload condition) is the sum of the overload recovery time and the slew time. The overload recovery time for the LM290xLV family is typically 1 µs.

#### 7.3.4 Electrical Overstress

Designers often ask questions about the capability of an operational amplifier to withstand electrical overstress. These questions tend to focus on the device inputs, but can also involve the supply voltage pins. Each of these different pin functions has electrical stress limits determined by the voltage breakdown characteristics of the particular semiconductor fabrication process and specific circuits connected to the pin. Additionally, internal electrostatic discharge (ESD) protection is built into these circuits to protect them from accidental ESD events both before and during product assembly.

Having a good understanding of this basic ESD circuitry and its relevance to an electrical overstress event is helpful. Figure 30 shows the ESD circuits contained in the LM290xLV. The ESD protection circuitry involves several current-steering diodes connected from the input and output pins and routed back to the internal power supply lines, where they meet at an absorption device internal to the operational amplifier. This protection circuitry is intended to remain inactive during normal circuit operation.

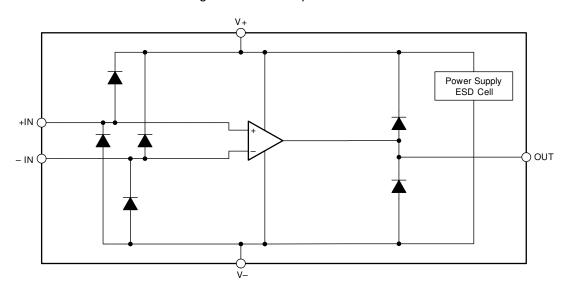


Figure 30. Equivalent Internal ESD Circuitry

#### 7.3.5 EMI Susceptibility and Input Filtering

Texas Instruments has developed the ability to accurately measure and quantify the immunity of an operational amplifier over a broad frequency spectrum extending from 10 MHz to 6 GHz. The Figure 28 plot illustrates the performance of the LM290xLV family's EMI filters across a wide range of frequencies. For more detailed information, see *EMI Rejection Ratio of Operational Amplifiers* available for download from www.ti.com.

#### 7.4 Device Functional Modes

The LM290xLV family has a single functional mode. The devices are powered on as long as the power-supply voltage is between 2.7 V ( $\pm$ 1.35 V) and 5.5 V ( $\pm$ 2.75 V).



## 8 Application and Implementation

#### NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

## 8.1 Application Information

The LM290xLV devices are a family of low-power, cost-optimized operational amplifiers. The devices operate from 2.7 V to 5.5 V, are unity-gain stable, and are suitable for a wide range of general-purpose applications. The input common-mode voltage range includes the negative rail, and allows the LM290xLV to be used in any single-supply applications.

#### 8.2 Typical Application

Figure 31 shows the LM290xLV device configured in a low-side current sensing application.

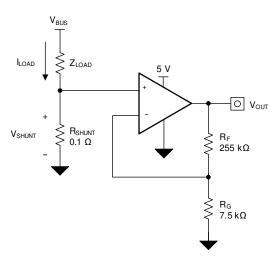


Figure 31. LM290xLV Device in a Low-Side, Current-Sensing Application

#### 8.2.1 Design Requirements

The design requirements for this design are:

Load current: 0 A to 1 AOutput voltage: 3.5 V

Maximum shunt voltage: 100 mV

### 8.2.2 Detailed Design Procedure

The transfer function of the circuit in Figure 31 is given in Equation 1:

$$V_{OUT} = I_{LOAD} \times R_{SHUNT} \times Gain$$
 (1)

The load current ( $I_{LOAD}$ ) produces a voltage drop across the shunt resistor ( $R_{SHUNT}$ ). The load current is set from 0 A to 1 A. To keep the shunt voltage below 100 mV at maximum load current, the largest allowable shunt resistor is shown using Equation 2:

$$R_{SHUNT} = \frac{V_{SHUNT\_MAX}}{I_{LOAD\_MAX}} = \frac{100mV}{1A} = 100m\Omega$$
(2)



#### **Typical Application (continued)**

Using Equation 2,  $R_{SHUNT}$  is calculated to be 100 m $\Omega$ . The voltage drop produced by  $I_{LOAD}$  and  $R_{SHUNT}$  is amplified by the LM290xLV device to produce an output voltage of approximately 0 V to 3.5 V. The gain needed by the LM290xLV to produce the necessary output voltage is calculated using Equation 3:

$$Gain = \frac{\left(V_{OUT\_MAX} - V_{OUT\_MIN}\right)}{\left(V_{IN\_MAX} - V_{IN\_MIN}\right)}$$
(3)

Using Equation 3, the required gain is calculated to be 35 V/V, which is set with resistors  $R_F$  and  $R_G$ . Equation 4 sizes the resistors  $R_F$  and  $R_G$ , to set the gain of the LM290xLV device to 35 V/V.

$$Gain = 1 + \frac{(R_F)}{(R_G)}$$
(4)

## 8.2.3 Application Curve

Selecting  $R_F$  as 255  $k\Omega$  and  $R_G$  as 7.5  $k\Omega$  provides a combination that equals 35 V/V. Figure 32 shows the measured transfer function of the circuit shown in Figure 31. Notice that the gain is only a function of the feedback and gain resistors. This gain is adjusted by varying the ratio of the resistors and the actual resistors values are determined by the impedance levels that the designer wants to establish. The impedance level determines the current drain, the effect that stray capacitance has, and a few other behaviors. There is no optimal impedance selection that works for every system, you must choose an impedance that is ideal for your system parameters.

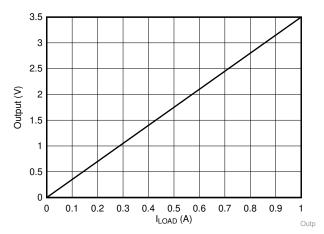


Figure 32. Low-Side, Current-Sense Transfer Function

17



## 9 Power Supply Recommendations

The LM290xLV family is specified for operation from 2.7 V to 5.5 V (±1.35 V to ±2.75 V); many specifications apply from -40°C to 125°C. The *Electrical Characteristics* section presents parameters that may exhibit significant variance with regard to operating voltage or temperature.

#### **CAUTION**

Supply voltages larger than 6 V may permanently damage the device; see the *Absolute Maximum Ratings* section.

Place 0.1-µF bypass capacitors close to the power-supply pins to reduce coupling errors from noisy or high-impedance power supplies. For more detailed information on bypass capacitor placement, see the *Layout Guidelines* section.

#### 9.1 Input and ESD Protection

The LM290xLV family incorporates internal ESD protection circuits on all pins. For input and output pins, this protection primarily consists of current-steering diodes connected between the input and power-supply pins. These ESD protection diodes provide in-circuit, input overdrive protection, as long as the current is limited to 10 mA, as stated in the *Absolute Maximum Ratings* section. Figure 33 shows how a series input resistor can be added to the driven input to limit the input current. The added resistor contributes thermal noise at the amplifier input and the value must be kept to a minimum in noise-sensitive applications.

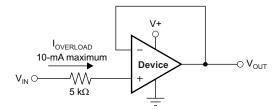


Figure 33. Input Current Protection



## 10 Layout

## 10.1 Layout Guidelines

For best operational performance of the device, use good printed circuit board (PCB) layout practices, including:

- Noise can propagate into analog circuitry through the power pins of the circuit as a whole and of the op amp itself. Bypass capacitors are used to reduce the coupled noise by providing low-impedance power sources local to the analog circuitry.
  - Connect low-ESR, 0.1-µF ceramic bypass capacitors between each supply pin and ground, placed as close to the device as possible. A single bypass capacitor from V+ to ground is applicable for singlesupply applications.
- Separate grounding for analog and digital portions of circuitry is one of the simplest and most effective
  methods of noise suppression. One or more layers on multilayer PCBs are usually devoted to ground
  planes. A ground plane helps distribute heat and reduces electromagnetic interference (EMI) noise
  pickup. Take care to physically separate digital and analog grounds. Use thermal signatures or EMI
  measurement techniques to determine where the majority of the ground current is flowing and be sure to
  route this path away from sensitive analog circuitry. For more detailed information, see Circuit Board
  Layout Techniques.
- To reduce parasitic coupling, run the input traces as far away from the supply or output traces as possible. If these traces cannot be kept separate, crossing the sensitive trace at a 90° angle is much better as opposed to running the traces in parallel with the noisy trace.
- Place the external components as close to the device as possible, as shown in Figure 35. Keeping R<sub>F</sub> and R<sub>G</sub> close to the inverting input minimizes parasitic capacitance.
- Keep the length of input traces as short as possible. Remember that the input traces are the most sensitive part of the circuit.
- Consider a driven, low-impedance guard ring around the critical traces. A guard ring may significantly reduce leakage currents from nearby traces that are at different potentials.
- Cleaning the PCB following board assembly is recommended for best performance.
- Any precision integrated circuit can experience performance shifts resulting from moisture ingress into the
  plastic package. Following any aqueous PCB cleaning process, baking the PCB assembly is
  recommended to remove moisture introduced into the device packaging during the cleaning process. A
  low-temperature, post-cleaning bake at 85°C for 30 minutes is sufficient for most circumstances.

#### 10.2 Layout Example

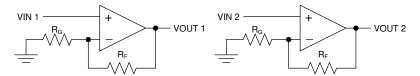


Figure 34. Schematic Representation for Figure 35



## Layout Example (接下页)

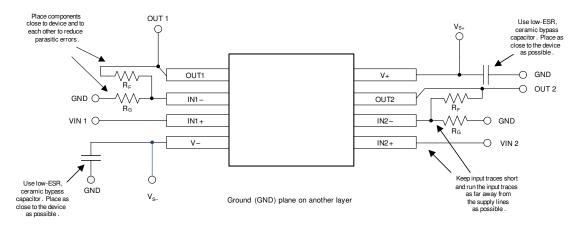


Figure 35. Layout Example



#### 器件和文档支持

#### 11.1 文档支持

#### 11.1.1 相关文档

请参阅如下相关文档:

德州仪器 (TI), 《运算放大器的 EMI 抑制比》

#### 11.2 相关链接

下表列出了快速访问链接。类别包括技术文档、支持和社区资源、工具和软件,以及立即订购快速访问。

表 1. 相关链接

器件	产品文件夹	立即订购	技术文档	工具与软件	支持和社区
LM2902LV	单击此处	单击此处	单击此处	单击此处	单击此处
LM2904LV	单击此处	单击此处	单击此处	单击此处	单击此处

#### 11.3 接收文档更新通知

要接收文档更新通知,请导航至 ti.com. 上的器件产品文件夹。单击右上角的通知我进行注册,即可每周接收产品 信息更改摘要。有关更改的详细信息,请查看任何已修订文档中包含的修订历史记录。

#### 11.4 社区资源

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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🗱 ESD 的损坏小至导致微小的性能降级,大至整个器件故障。 精密的集成电路可能更容易受到损坏,这是因为非常细微的参数更改都可 能会导致器件与其发布的规格不相符。

#### 11.7 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

## 12 机械、封装和可订购信息

以下页面包含机械、封装和可订购信息。这些信息是指定器件的最新可用数据。数据如有变更,恕不另行通知,且 不会对此文档进行修订。如需获取此数据表的浏览器版本,请查看左侧的导航面板。





10-Dec-2020

#### PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
LM2902LVIDR	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	LM2902LV	Samples
LM2902LVIPWR	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	SN	Level-2-260C-1 YEAR	-40 to 125	LM2902LV	Samples
LM2904LVIDDFR	ACTIVE	SOT-23-THIN	DDF	8	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	L904	Samples
LM2904LVIDGKR	ACTIVE	VSSOP	DGK	8	2500	RoHS & Green	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	1SQX	Samples
LM2904LVIDR	ACTIVE	SOIC	D	8	2500	RoHS & Green	SN	Level-2-260C-1 YEAR	-40 to 125	2904LV	Samples
LM2904LVIPWR	ACTIVE	TSSOP	PW	8	2000	RoHS & Green	NIPDAU   SN	Level-2-260C-1 YEAR	-40 to 125	2904	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.



## **PACKAGE OPTION ADDENDUM**

10-Dec-2020

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

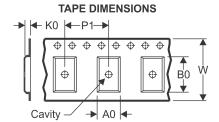
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

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## TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

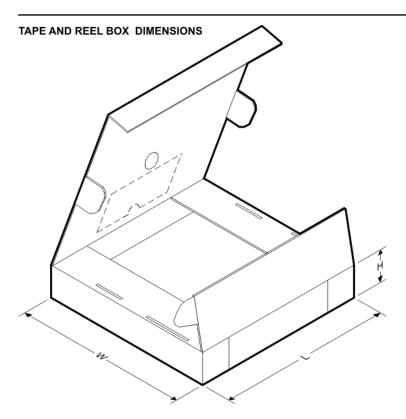
## QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LM2902LVIDR	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
LM2902LVIDR	SOIC	D	14	2500	330.0	15.4	6.4	5.2	2.1	8.0	12.0	Q1
LM2902LVIPWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
LM2904LVIDDFR	SOT- 23-THIN	DDF	8	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
LM2904LVIDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
LM2904LVIDR	SOIC	D	8	2500	330.0	15.4	6.4	5.2	2.1	8.0	12.0	Q1
LM2904LVIPWR	TSSOP	PW	8	2000	330.0	12.4	7.0	3.6	1.6	8.0	12.0	Q1
LM2904LVIPWR	TSSOP	PW	8	2000	330.0	12.4	7.0	3.6	1.6	8.0	12.0	Q1

www.ti.com 29-Jun-2021



\*All dimensions are nominal

All differences are normal								
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
LM2902LVIDR	SOIC	D	14	2500	853.0	449.0	35.0	
LM2902LVIDR	SOIC	D	14	2500	336.6	336.6	41.3	
LM2902LVIPWR	TSSOP	PW	14	2000	366.0	364.0	50.0	
LM2904LVIDDFR	SOT-23-THIN	DDF	8	3000	210.0	185.0	35.0	
LM2904LVIDGKR	VSSOP	DGK	8	2500	366.0	364.0	50.0	
LM2904LVIDR	SOIC	D	8	2500	336.6	336.6	41.3	
LM2904LVIPWR	TSSOP	PW	8	2000	366.0	364.0	50.0	
LM2904LVIPWR	TSSOP	PW	8	2000	853.0	449.0	35.0	

## D (R-PDSO-G14)

## PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AB.



# D (R-PDSO-G14)

## PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



PW (R-PDSO-G14)

## PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



# PW (R-PDSO-G14)

## PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.





SMALL OUTLINE INTEGRATED CIRCUIT



- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



# DGK (S-PDSO-G8)

# PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per end.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- E. Falls within JEDEC MO-187 variation AA, except interlead flash.



# DGK (S-PDSO-G8)

## PLASTIC SMALL OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.





SMALL OUTLINE PACKAGE



- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153, variation AA.



SMALL OUTLINE PACKAGE



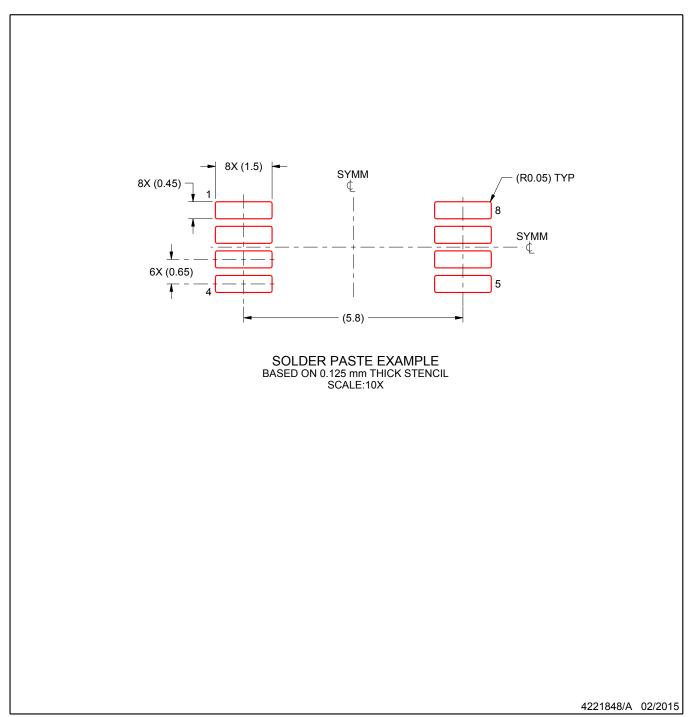
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



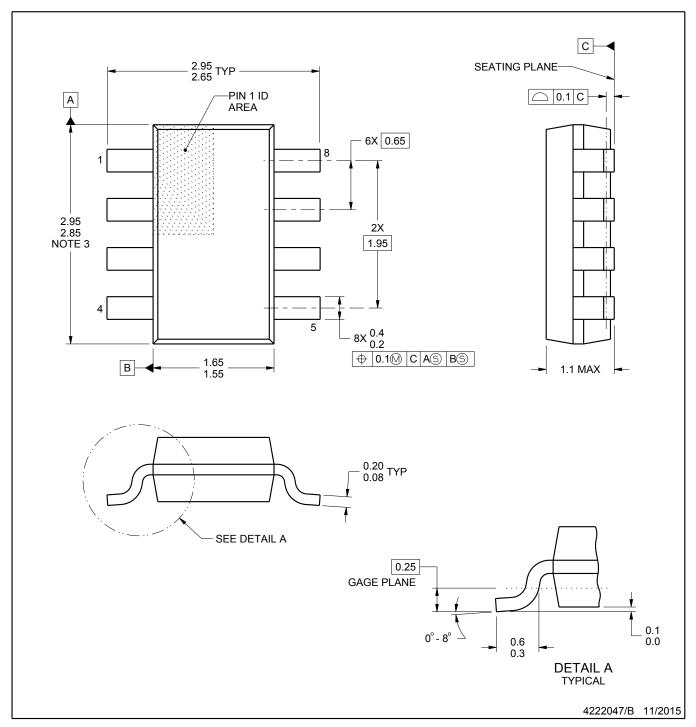
NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





PLASTIC SMALL OUTLINE



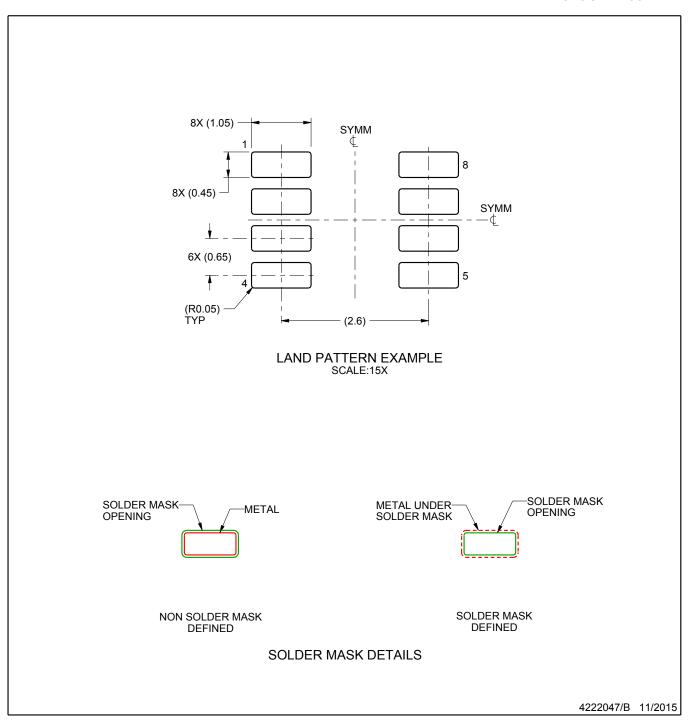
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.



PLASTIC SMALL OUTLINE

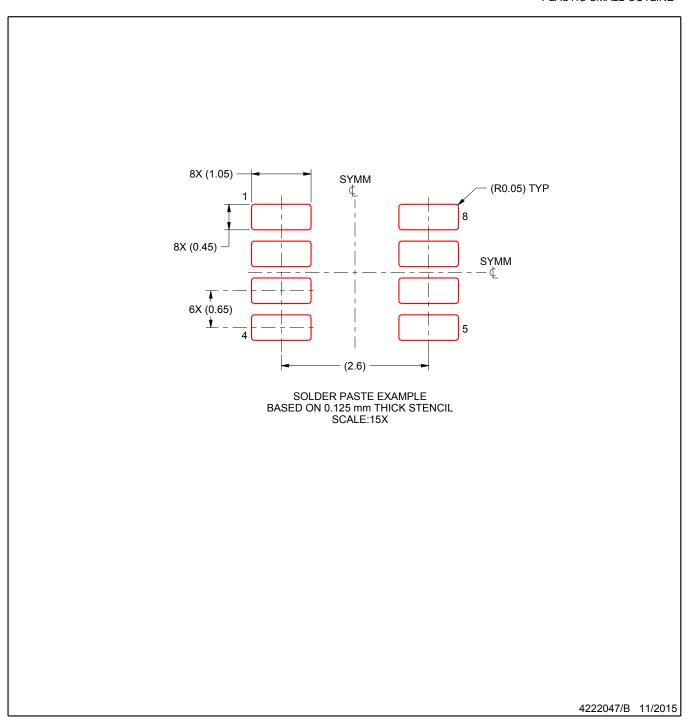


NOTES: (continued)

- 4. Publication IPC-7351 may have alternate designs.
- 5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



PLASTIC SMALL OUTLINE



NOTES: (continued)

- 6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 7. Board assembly site may have different recommendations for stencil design.



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